

# Yasuo Cho

## List of Publications by Year in descending order

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156  
papers

3,501  
citations

147801

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53  
g-index

157  
all docs

157  
docs citations

157  
times ranked

2105  
citing authors

#	ARTICLE	IF	CITATIONS
1	Scanning nonlinear dielectric microscope. Review of Scientific Instruments, 1996, 67, 2297-2303.	1.3	243
2	Tbit/inch <sup>2</sup> ferroelectric data storage based on scanning nonlinear dielectric microscopy. Applied Physics Letters, 2002, 81, 4401-4403.	3.3	186
3	Scanning nonlinear dielectric microscopy with nanometer resolution. Applied Physics Letters, 1999, 75, 2833-2835.	3.3	177
4	Sample collection from asteroid (162173) Ryugu by Hayabusa2: Implications for surface evolution. Science, 2020, 368, 654-659.	12.6	158
5	Nonlinear, elastic, piezoelectric, electrostrictive, and dielectric constants of lithium niobate. Journal of Applied Physics, 1987, 61, 875-887.	2.5	146
6	Effects of deposition conditions on the ferroelectric properties of (Al <sub>1-x</sub> Sc <sub>x</sub> )N thin films. Journal of Applied Physics, 2020, 128, .	2.5	127
7	Microscale to nanoscale ferroelectric domain and surface engineering of a near-stoichiometric LiNbO <sub>3</sub> crystal. Applied Physics Letters, 2003, 82, 433-435.	3.3	117
8	Nanodomain manipulation for ultrahigh density ferroelectric data storage. Nanotechnology, 2006, 17, S137-S141.	2.6	79
9	Scanning Nonlinear Dielectric Microscope Using a Lumped Constant Resonator Probe and Its Application to Investigation of Ferroelectric Polarization Distributions. Japanese Journal of Applied Physics, 1997, 36, 3152-3156.	1.5	78
10	Scanning Nonlinear Dielectric Microscopy Nano-Science and Technology for Next Generation High Density Ferroelectric Data Storage. Japanese Journal of Applied Physics, 2008, 47, 3311.	1.5	73
11	Realization of 10Tbit·in. <sup>2</sup> memory density and subnanosecond domain switching time in ferroelectric data storage. Applied Physics Letters, 2005, 87, 232907.	3.3	69
12	Simultaneous observation of nano-sized ferroelectric domains and surface morphology using scanning nonlinear dielectric microscopy. Surface Science, 2000, 463, L621-L625.	1.9	64
13	Theoretical and Experimental Study on Nanoscale Ferroelectric Domain Measurement Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2000, 39, 5719-5722.	1.5	54
14	The influence of 180° ferroelectric domain wall width on the threshold field for wall motion. Journal of Applied Physics, 2008, 104, 084107.	2.5	53
15	Ferroelectric properties of an epitaxial lead zirconate titanate thin film deposited by a hydrothermal method below the Curie temperature. Applied Physics Letters, 2004, 84, 5094-5096.	3.3	52
16	Atomic Dipole Moment Distribution of Si Atoms on a $\text{Si}_{111}$ $\hat{a}'$ $\text{Si}_{7\bar{7}\bar{7}}$ Tj ETQq0 0 0 rgBT /Ov	7.8	52
17	Dielectric properties of a hydrothermally deposited epitaxial lead titanate thin film on strontium ruthenium oxide bottom electrode. Applied Physics Letters, 2004, 85, 2331-2333.	3.3	45
18	Charge gradient microscopy. Proceedings of the National Academy of Sciences of the United States of America, 2014, 111, 6566-6569.	7.1	44

#	ARTICLE	IF	CITATIONS
19	Non-contact scanning nonlinear dielectric microscopy. Nanotechnology, 2005, 16, S54-S58. <mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML"><mml:mi>A</mml:mi></mml:math>-site-driven ferroelectricity in strained ferromagnetic	2.6	42
20	<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML"><mml:msub><mml:mi mathvariant="normal">La</mml:mi></mml:msub><mml:mn>2</mml:mn></mml:math><mml:msub><mml:mi mathvariant="normal">NiMnO</mml:mi></mml:msub></mml:math> thin films.	3.2	42
21	Terabit inch <sup>2</sup> ferroelectric data storage using scanning nonlinear dielectric microscopy nanodomain engineering system. Nanotechnology, 2003, 14, 637-642.	2.6	40
22	High-speed switching of nanoscale ferroelectric domains in congruent single-crystal LiTaO <sub>3</sub> . Applied Physics Letters, 2003, 83, 5265-5267.	3.3	40
23	Scanning nonlinear dielectric microscopy. Journal of Materials Research, 2011, 26, 2007-2016.	2.6	40
24	Polarization reversal anti-parallel to the applied electric field observed using a scanning nonlinear dielectric microscopy. Applied Physics Letters, 2004, 84, 257-259.	3.3	39
25	Actual information storage with a recording density of 4 Tbit/in. <sup>2</sup> in a ferroelectric recording medium. Applied Physics Letters, 2010, 97, 092901.	3.3	35
26	Epitaxial PbTiO <sub>3</sub> Thin Films on SrTiO <sub>3</sub> (100) and SrRuO <sub>3</sub> /SrTiO <sub>3</sub> (100) Substrates Deposited by a Hydrothermal Method. Japanese Journal of Applied Physics, 2004, 43, 6535-6538.	1.5	34
27	Quantitative Measurement of Linear and Nonlinear Dielectric Characteristics Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2000, 39, 3086-3089.	1.5	33
28	Domain structure in a micron-sized PbZr <sub>1-x</sub> Ti <sub>x</sub> O <sub>3</sub> single crystal on a Ti substrate fabricated by hydrothermal synthesis. Applied Physics Letters, 2004, 84, 3346-3348.	3.3	33
29	Multiferroism at Room Temperature in BiFeO <sub>3</sub> /BiCrO <sub>3</sub> (111) Artificial Superlattices. Applied Physics Express, 2008, 1, 101302.	2.4	33
30	Ferroelectric property of an epitaxial lead zirconate titanate thin film deposited by a hydrothermal method. Journal of Materials Research, 2004, 19, 1862-1868.	2.6	32
31	Visualization of charges stored in the floating gate of flash memory by scanning nonlinear dielectric microscopy. Nanotechnology, 2006, 17, S185-S188.	2.6	32
32	Cross-sectional dopant profiling and depletion layer visualization of SiC power double diffused metal-oxide-semiconductor field effect transistor using super-higher-order nonlinear dielectric microscopy. Journal of Applied Physics, 2014, 116, .	2.5	32
33	Dynamic Measuring Method of Capacitance Variation of Piezoelectric Ceramics with Alternating Electric Field. Japanese Journal of Applied Physics, 1992, 31, 3627-3631.	1.5	31
34	Observation of the Si(111)7 Å—7 atomic structure using non-contact scanning nonlinear dielectric microscopy. Nanotechnology, 2007, 18, 084014.	2.6	31
35	Interfacial Charge States in Graphene on SiC Studied by Noncontact Scanning Nonlinear Dielectric Potentiometry. Physical Review Letters, 2015, 114, 226103.	7.8	31
36	Single crystal growth of KNbO <sub>3</sub> and application to surface acoustic wave devices. Journal of the European Ceramic Society, 2001, 21, 2791-2795.	5.7	30

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37	Surface acoustic wave soliton propagating on the metallic grating waveguide. Applied Physics Letters, 1993, 63, 1188-1190.	3.3	29
38	Measurement of the Ferroelectric Domain Distributions Using Nonlinear Dielectric Response and Piezoelectric Response. Japanese Journal of Applied Physics, 2001, 40, 3534-3537.	1.5	29
39	Piezoelectric property of an epitaxial lead titanate thin film deposited by the hydrothermal method. Applied Physics Letters, 2006, 88, 112908.	3.3	29
40	Influence of Rare Earth Ions on BaO-TiO <sub>2</sub> -Rare Earth Oxide Ceramics for Microwave Applications. Japanese Journal of Applied Physics, 1993, 32, 1712-1715.	1.5	28
41	Observation of domain walls in PbZr <sub>0.2</sub> Ti <sub>0.8</sub> O <sub>3</sub> thin film using scanning nonlinear dielectric microscopy. Applied Physics Letters, 2003, 83, 2650-2652.	3.3	28
42	Scanning Nonlinear Dielectric Microscopy with Contact Sensing Mechanism for Observation of Nanometer Sized Ferroelectric Domains. Japanese Journal of Applied Physics, 1999, 38, 5689-5694.	1.5	26
43	Development of scanning microwave microscope with a lumped-constant resonator probe for high-throughput characterization of combinatorial dielectric materials. Applied Surface Science, 2002, 189, 222-226.	6.1	25
44	Observation of Ultrathin Single-Domain Layers Formed on LiTaO <sub>3</sub> and LiNbO <sub>3</sub> Surfaces Using Scanning Nonlinear Dielectric Microscope with Submicron Resolution. Japanese Journal of Applied Physics, 1999, 38, 3279-3282.	1.5	23
45	Ultrahigh-Density Ferroelectric Data Storage Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2003, 42, 6050-6054.	1.5	23
46	Effect of the surface adsorbed water on the studying of ferroelectrics by scanning nonlinear dielectric microscopy. Journal of Applied Physics, 2004, 96, 7460-7463.	2.5	23
47	Nanosecond microscopy of capacitance at SiO <sub>2</sub> /4H-SiC interfaces by time-resolved scanning nonlinear dielectric microscopy. Applied Physics Letters, 2017, 111, .	3.3	23
48	Simultaneous Observation of Ferroelectric Domain Patterns by Scanning Nonlinear Dielectric Microscope and Surface Morphology by Atomic Force Microscope. Japanese Journal of Applied Physics, 2000, 39, 3808-3810.	1.5	22
49	Scanning-nonlinear-dielectric-microscopy study on periodically poled LiNbO <sub>3</sub> for a high-performance quasi-phase matching device. Applied Physics Letters, 2001, 79, 2955-2957.	3.3	22
50	High resolution characterizations of fine structure of semiconductor device and material using scanning nonlinear dielectric microscopy. Japanese Journal of Applied Physics, 2017, 56, 100101.	1.5	22
51	Determination of the Polarities of ZnO Thin Films on Polar and Nonpolar Substrates Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2000, 39, 3121-3124.	1.5	21
52	Measuring ferroelectric polarization component parallel to the surface by scanning nonlinear dielectric microscopy. Applied Physics Letters, 2002, 80, 2159-2161.	3.3	21
53	Visualization using scanning nonlinear dielectric microscopy of electrons and holes localized in the thin gate film of a metal-oxide-semiconductor flash memory. Applied Physics Letters, 2005, 86, 013501.	3.3	21
54	Local deep level transient spectroscopy using super-higher-order scanning nonlinear dielectric microscopy and its application to imaging two-dimensional distribution of SiO <sub>2</sub> /SiC interface traps. Journal of Applied Physics, 2017, 122, .	2.5	21

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55	Visualization of electrons and holes localized in gate thin film of metal SiO <sub>2</sub> /Si <sub>3</sub> N <sub>4</sub> /SiO <sub>2</sub> semiconductor-type flash memory using scanning nonlinear dielectric microscopy after writing-erasing cycling. Applied Physics Letters, 2005, 86, 063515.	3.3	20
56	Piezoelectric Performance and Domain Structure of Epitaxial PbTiO <sub>3</sub> Thin Film Deposited by Hydrothermal Method. Japanese Journal of Applied Physics, 2006, 45, 4489-4492.	1.5	20
57	Characterization of Ferroelectric Property of C-Axis- and Non-C-Axis-Oriented Epitaxially Grown Bi <sub>2</sub> VO <sub>5</sub> Thin Films. Japanese Journal of Applied Physics, 2001, 40, 6481-6486.	1.5	19
58	Cross-sectional observation of nanodomain dots formed in both congruent and stoichiometric LiTaO <sub>3</sub> crystals. Applied Physics Letters, 2007, 90, 192906.	3.3	19
59	Two-dimensional defect mapping of the SiO <sub>2</sub> /Si <sub>3</sub> N <sub>4</sub> /SiO <sub>2</sub> interface. Physical Review Materials, 2019, 3, .	3.3	18
60	Wall behavior of nanodomains as a function of their initial state. Applied Physics Letters, 2006, 89, 192906.	3.3	18
61	Scanning nonlinear dielectric potentiometry. Review of Scientific Instruments, 2015, 86, 093704.	1.3	18
62	Evaluation of Bit Error Rate for Ferroelectric Data Storage. Japanese Journal of Applied Physics, 2004, 43, 6632-6634.	1.5	17
63	Quantitative Measurement of Linear Dielectric Constant Using Scanning Nonlinear Dielectric Microscopy with Electro-Conductive Cantilever. Japanese Journal of Applied Physics, 2002, 41, 4961-4964.	1.5	16
64	High-density ferroelectric recording using a hard disk drive-type data storage system. Journal of Applied Physics, 2016, 119, .	2.5	16
65	Visualization of electrons and holes localized in the thin gate film of metal-oxide-nitride-oxide-semiconductor type Flash memory by scanning nonlinear dielectric microscopy. Nanotechnology, 2005, 16, S90-S93.	2.6	15
66	Quantitative measurement of active dopant density distribution in phosphorus-implanted monocrystalline silicon solar cell using scanning nonlinear dielectric microscopy. Applied Physics Letters, 2017, 111, .	3.3	15
67	Fundamental Study on Nano Domain Engineering Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2001, 40, 4354-4356.	1.5	14
68	Nanosecond Switching of Nanoscale Ferroelectric Domains in Congruent Single-Crystal LiTaO <sub>3</sub> Using Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2004, 43, 2818-2821.	1.5	14
69	Nanodomain Formation on Ferroelectrics and Development of Hard-Disk-Drive-Type Ferroelectric Data Storage Devices. Japanese Journal of Applied Physics, 2009, 48, 09KA18.	1.5	14
70	Lateral resolution improvement in scanning nonlinear dielectric microscopy by measuring super-higher-order nonlinear dielectric constants. Applied Physics Letters, 2012, 101, .	3.3	14
71	Photothermal dielectric spectroscopic microscope. Review of Scientific Instruments, 1996, 67, 19-28.	1.3	13
72	Evaluation of silicon- and carbon-face SiO <sub>2</sub> /SiC MOS interface quality based on scanning nonlinear dielectric microscopy. Applied Physics Letters, 2017, 111, .	3.3	13

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73	Dynamic method for measuring the velocity variation of ultrasound in piezoelectric ceramics with an alternating electric field. <i>Review of Scientific Instruments</i> , 1993, 64, 1244-1247.	1.3	12
74	Observation of Ferroelectric Polarization in the Noncontact Mode of a Scanning Nonlinear Dielectric Microscope. <i>Japanese Journal of Applied Physics</i> , 1997, 36, 360-363.	1.5	12
75	New Functions of Scanning Nonlinear Dielectric Microscopy â€œHigher-Order Measurement and Vertical Resolutionâ€œ. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 3544-3548.	1.5	12
76	Higher Order Nonlinear Dielectric Imaging Using Scanning Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 4349-4353.	1.5	12
77	Scanning Nonlinear Dielectric Microscope with Super High Resolution. <i>Japanese Journal of Applied Physics</i> , 2007, 46, 4428.	1.5	12
78	Interfacial capacitance between a ferroelectric Fe <sub>3</sub> O <sub>4</sub> thin film and a semiconducting Nb:SrTiO <sub>3</sub> substrate. <i>Journal of Applied Physics</i> , 2015, 117, 014104.	2.5	12
79	Scanning probe-type data storage beyond hard disk drive and flash memory. <i>MRS Bulletin</i> , 2018, 43, 365-370.	3.5	11
80	Fundamental Study of Surface Layer on Ferroelectrics by Scanning Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2001, 40, 5833-5836.	1.5	10
81	Atomic dipole moment distribution on a hydrogen-adsorbed Si(111)-(7Å×7) surface observed by noncontact scanning nonlinear dielectric microscopy. <i>Applied Physics Letters</i> , 2013, 103, .	3.3	10
82	Novel HDD-type SNDM ferroelectric data storage system aimed at high-speed data transfer with single probe operation. <i>IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control</i> , 2007, 54, 2523-2528.	3.0	9
83	Investigation of interface between fullerene molecule and Si(111)-7Å×7 surface by noncontact scanning nonlinear dielectric microscopy. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2010, 28, C4D18-C4D23.	1.2	9
84	Observation of electrochemical capacitance in a graphite surface by noncontact scanning nonlinear dielectric microscopy. <i>Physical Review B</i> , 2010, 82, .	3.2	9
85	Three-dimensional observation of nanoscale ferroelectric domains using scanning nonlinear dielectric microscopy with electric field correction by Kelvin probe force microscopy. <i>Nanotechnology</i> , 2006, 17, S162-S166.	2.6	8
86	Observations of Domain Structure and Ferroelectricity in Bi(Ni <sub>0.5</sub> Ti <sub>0.5</sub> )O <sub>3</sub> Ceramics Fabricated by High-pressure Sintering. <i>Chemistry Letters</i> , 2008, 37, 560-561.	1.3	8
87	Observation of dopant profile of transistors using scanning nonlinear dielectric microscopy. <i>Journal of Physics: Conference Series</i> , 2010, 209, 012050.	0.4	8
88	Local deep level transient spectroscopy using super-higher-order scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2016, 64, 566-569.	1.7	8
89	Visualization of Gate-Bias-Induced Carrier Redistribution in SiC Power DIMOSFET Using Scanning Nonlinear Dielectric Microscopy. <i>IEEE Transactions on Electron Devices</i> , 2016, 63, 3165-3170.	3.0	8
90	Intermittent contact scanning nonlinear dielectric microscopy. <i>Review of Scientific Instruments</i> , 2010, 81, 023705.	1.3	7

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91	Improved study of electric dipoles on the Si(100)- $2 \times 1$ surface by non-contact scanning nonlinear dielectric microscopy. Applied Physics Letters, 2014, 105, 101603.	3.3	7
92	Visualization and analysis of active dopant distribution in a p-i-n structured amorphous silicon solar cell using scanning nonlinear dielectric microscopy. AIP Advances, 2015, 5, .	1.3	7
93	Three-Dimensional Measurement for Absolute Value of Polarization Angle by Scanning Nonlinear Dielectric Microscopy. Japanese Journal of Applied Physics, 2005, 44, 4325-4329.	1.5	6
94	Pb(Zr,Ti)O <sub>3</sub> recording media for probe data storage devices prepared by rf magnetron sputtering. Japanese Journal of Applied Physics, 2014, 53, 09PA05.	1.5	6
95	Simultaneous observation of two dimensional electron gas and polarization in AlGaN/GaN heterostructure using scanning nonlinear dielectric microscopy. Japanese Journal of Applied Physics, 2016, 55, 08NB13.	1.5	6
96	Local carrier distribution imaging on few-layer MoS <sub>2</sub> exfoliated on SiO <sub>2</sub> by scanning nonlinear dielectric microscopy. Applied Physics Letters, 2018, 112, .	3.3	6
97	Influence of Non-Uniform Interface Defect Clustering on Field-Effect Mobility in SiC MOSFETs Investigated by Local Deep Level Transient Spectroscopy and Device Simulation. Materials Science Forum, 0, 1004, 627-634.	0.3	6
98	Atomic-dipole-moment induced local surface potential on Si(111)- $7 \times 7$ surface studied by non-contact scanning nonlinear dielectric microscopy. Applied Physics Letters, 2014, 105, 121601.	3.3	5
99	New microscope for measuring the distribution of nonlinear dielectric properties. Electronics and Communications in Japan, 1996, 79, 68-75.	0.2	4
100	Scanning nonlinear dielectric microscopy observation of accumulated charges in metal-SiO <sub>2</sub> -SiN-SiO <sub>2</sub> -Si flash memory by detecting higher-order nonlinear permittivity. Applied Physics Letters, 2012, 101, 242101.	3.3	4
101	Measurements of Nonlinear Dielectric Constants of Pb(Zr,Ti)O <sub>3</sub> Thin Films Using a Dynamic Measuring Method. Japanese Journal of Applied Physics, 2013, 52, 09KA08.	1.5	4
102	Dynamic observation of ferroelectric domain switching using scanning nonlinear dielectric microscopy. Japanese Journal of Applied Physics, 2017, 56, 10PF16.	1.5	4
103	Nanoscale linear permittivity imaging based on scanning nonlinear dielectric microscopy. Nanotechnology, 2018, 29, 205709.	2.6	4
104	High resolution observation of defects at SiO <sub>2</sub> /4H-SiC interfaces using time-resolved scanning nonlinear dielectric microscopy. Microelectronics Reliability, 2018, 88-90, 242-245.	1.7	4
105	Visualization of traps at SiO <sub>2</sub> /SiC interfaces near the conduction band by local deep level transient spectroscopy at low temperatures. Japanese Journal of Applied Physics, 2018, 57, 08NB12.	1.5	4
106	Boxcar Averaging Based Scanning Nonlinear Dielectric Microscopy and Its Application to Carrier Distribution Imaging on 2D Semiconductors. , 2019, , .		4
107	A Study on Evaluation of Interface Defect Density on High-K/SiO <sub>2</sub> /Si and SiO <sub>2</sub> /Si Gate Stacks using Scanning Nonlinear Dielectric Microscopy. , 2019, , .		4
108	Nanoscale characterization of unintentional doping of atomically thin layered semiconductors by scanning nonlinear dielectric microscopy. Journal of Applied Physics, 2020, 128, .	2.5	4

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109	Spatial scale dependent impact of non-uniform interface defect distribution on field effect mobility in SiC MOSFETs. <i>Microelectronics Reliability</i> , 2020, 114, 113829.	1.7	4
110	Profiling of carriers in a 3D flash memory cell with nanometer-level resolution using scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2020, 114, 113774.	1.7	4
111	Local $C\text{-}V$ mapping for ferroelectrics using scanning nonlinear dielectric microscopy. <i>Journal of Applied Physics</i> , 2020, 128, 244105.	2.5	4
112	Determination of the Temperature Coefficient Distribution of Dielectric Ceramics Using Scanning Photothermal Dielectric Microscopy. <i>Journal of the American Ceramic Society</i> , 1999, 82, 1720-1724.	3.8	3
113	Determination of Electrostrictive and Third-Order Dielectric Constants of Piezoelectric Ceramic. <i>Japanese Journal of Applied Physics</i> , 2000, 39, 3524-3527.	1.5	3
114	Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy. <i>Journal of the European Ceramic Society</i> , 2001, 21, 1581-1584.	5.7	3
115	Scanning nonlinear dielectric microscopy. <i>Advances in Imaging and Electron Physics</i> , 2003, 127, 1-57.	0.2	3
116	Characterization and comparison of nanoscale domain boundary in congruent and stoichiometric LiTaO <sub>3</sub> with scanning nonlinear dielectric microscopy. <i>Applied Physics Letters</i> , 2009, 95, 022908.	3.3	3
117	New evaluation of fullerene molecules on Si(111)-(7 $\times$ 7) reconstructed structure using non-contact scanning non-linear dielectric microscopy. <i>Surface Science</i> , 2012, 606, 174-180.	1.9	3
118	Optimization of signal intensity in intermittent contact scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2019, 100-101, 113345.	1.7	3
119	Local capacitance-voltage profiling and high voltage stress effect study of SiO <sub>2</sub> /SiC structures by time-resolved scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2021, 126, 114284.	1.7	3
120	Active control of nonlinear piezoelectric effect and its application to 20 dB efficiency improvement of SAW elastic convolver. , 1994, , .		2
121	Experimental study of electric dipoles on an oxygen-adsorbed Si(100)-2 $\times$ 1 surface by non-contact scanning nonlinear dielectric microscopy. <i>Applied Physics Letters</i> , 2015, 107, 031604.	3.3	2
122	Noncontact scanning nonlinear dielectric microscopy. , 2020, , 95-112.		2
123	Observation of Nanoscale Ferroelectric Domains Using Super-Higher-Order Nonlinear Dielectric Microscopy. <i>Japanese Journal of Applied Physics</i> , 2012, 51, 09LE07.	1.5	2
124	Surface Potential Fluctuations of SiO <sub>2</sub> /SiC Interfaces Investigated by Local Capacitance-Voltage Profiling Based on Time-Resolved Scanning Nonlinear Dielectric Microscopy. <i>Materials Science Forum</i> , 0, 1062, 335-340.	0.3	2
125	Local capacitance-voltage profiling and deep level transient spectroscopy of SiO <sub>2</sub> /SiC interfaces by scanning nonlinear dielectric microscopy. <i>Microelectronics Reliability</i> , 2022, 135, 114588.	1.7	2
126	High resolution imaging in cross-section of a metal-oxide-semiconductor field-effect-transistor using super-higher-order nonlinear dielectric microscopy. <i>Journal of Physics: Conference Series</i> , 2013, 471, 012023.	0.4	1

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127	Two-dimensional analysis of carrier distribution in phosphorus-implanted emitter and phosphorus-diffused emitter using super-higher-order scanning nonlinear dielectric microscopy. , 2016, , .		1
128	Carrier distribution imaging using $\hat{C}, \hat{z}$ -mode scanning nonlinear dielectric microscopy. Review of Scientific Instruments, 2019, 90, 083705.	1.3	1
129	A scanning nonlinear dielectric microscopic investigation of potential-induced degradation in monocrystalline silicon solar cells. Applied Physics Letters, 2020, 116, 182107.	3.3	1
130	Material Design Strategy for Enhancement of Readback Signal Intensity in Ferroelectric Probe Data Storage. IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control, 2021, 68, 859-864.	3.0	1
131	High-precision local $\hat{C}$ mapping for ferroelectrics using principal component analysis. Japanese Journal of Applied Physics, 2021, 60, SFFB09.	1.5	1
132	Nanoscale capacitance-voltage profiling of DC bias induced stress on a high- $\hat{C}$ /SiO <sub>2</sub> /Si gate stack. Microelectronics Reliability, 2021, 126, 114278.	1.7	1
133	Local Capacitance-Voltage Profiling and Deep Level Transient Spectroscopy of SiO <sub>2</sub> /SiC Interfaces by Scanning Nonlinear Dielectric Microscopy. , 2021, , .		1
134	Boxcar Averaging Scanning Nonlinear Dielectric Microscopy. Nanomaterials, 2022, 12, 794.	4.1	1
135	Microscopic Evaluation of Al<sub>2</sub>O<sub>3</sub>/p-Type Diamond (111) Interfaces Using Scanning Nonlinear Dielectric Microscopy. Materials Science Forum, 0, 1062, 298-303.	0.3	1
136	Relations between the constants of electrostrictive materials and some examples of their application to piezoelectric ceramics. Electronics and Communications in Japan, Part III: Fundamental Electronic Science (English Translation of Denshi Tsushin Gakkai Ronbunshi), 1993, 76, 20-30.	0.1	0
137	Dynamic measurement of nonlinear constants of PZT ceramics. Electronics and Communications in Japan, Part III: Fundamental Electronic Science (English Translation of Denshi Tsushin Gakkai) Tj ETQq1 1 0.7843140gBT /Overlock 10		0
138	Experimental demonstration of the reduction of the number of independent electrostrictive constants of piezoelectric ceramics. , 1994, , .		0
139	Scanning nonlinear dielectric microscope for investigation of polarization distributions. , 0, , .		0
140	Microscopic observation of the temperature coefficient distribution of dielectric material for microwave application using scanning photothermal dielectric microscope. , 0, , .		0
141	Quantitative Imaging of MOS Interface Trap Distribution by Using Local Deep Level Transient Spectroscopy. , 2018, , .		0
142	Improvement of Local Deep Level Transient Spectroscopy for Microscopic Evaluation of SiO <sub>2</sub> /4H-SiC Interfaces. Materials Science Forum, 2018, 924, 289-292.	0.3	0
143	High Resolution Mapping of Defects at SiO <sub>2</sub> /SiC Interfaces by Local-DLTS Based on Time-Resolved Scanning Nonlinear Dielectric Microscopy. , 2019, , .		0
144	Spatially-Resolved Evaluation of Interface Defect Density on Macrostepped SiO <sub>2</sub> /SiC using Local Deep Level Transient Spectroscopy. , 2019, , .		0

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145	Carrier distribution measurement in semiconductor materials and devices. , 2020, , 153-174.		0
146	Linear permittivity measurement by scanning nonlinear dielectric microscopy. , 2020, , 75-94.		0
147	Principles of scanning nonlinear dielectric microscopy for semiconductor measurement. , 2020, , 141-151.		0
148	Super-higher-order scanning nonlinear dielectric microscopy. , 2020, , 175-188.		0
149	Local deep-level transient spectroscopy. , 2020, , 189-219.		0
150	Time-resolved scanning nonlinear dielectric microscopy. , 2020, , 221-238.		0
151	Local C-V Characterization for Ferroelectric Films. , 2021, , .		0
152	Introduction of Scanning Nonlinear Dielectric Microscopy and Its Applications to the Evaluation of Electronic Materials and Devices. Journal of the Institute of Electrical Engineers of Japan, 2017, 137, 697-700.	0.0	0
153	Simulation of nanoscale domain growth for ferroelectric recording. AIP Advances, 2021, 11, 115117.	1.3	0
154	Development of nonlinear dielectric microscope and its application to measurement of ferroelectric polarization. , 0, , .		0
155	Carrier profile mapping in a 3D Flash memory cell using scanning nonlinear dielectric microscopy. , 2022, , .		0
156	Local capacitance-voltage profiling on MoS <sub>2</sub> /SiO <sub>2</sub> and MoS <sub>2</sub> /h-BN/SiO <sub>2</sub> by scanning nonlinear dielectric microscopy assisted with an insulating tip. , 2022, , .		0